

MLC: a machine learning based checker for soft error detection in embedded processors

Nosrati, Nooshin; **Jenihhin, Maksim**; Navabi, Zainalabedin Proceedings - 2022 IEEE 28th International Symposium on On-Line Testing and Robust System Design, IOLTS 2022 2022 / Code 183305 <https://doi.org/10.1109/IOLTS56730.2022.9897309> [Article at Scopus](#) [Article at WOS](#)

Universal mitigation of NBTI-induced aging by design randomization

Jenihhin, Maksim; Kamkin, Alexander; Navabi, Zainalabedin; Sadeghi-Kohan, Somayeh Proceedings of 2016 IEEE East-West Design & Test Symposium (EWDTS) : Yerevan, Armenia, October 14-17, 2016 2017 / [5] p. : ill
<http://dx.doi.org/10.1109/EWDTS.2016.7807635>